Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

241072US2SRD

SERIAL NO.

10/629,624

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Naoki SHUTOH, et al.

FILING DATE

July 30, 2003

GROUP

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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					YES	NO
ADF	AO	2001-189495	07/10/2001	JAPAN		X
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ADF	AW	H. HOHL, et al., J. Phys.: Condens., matter 11, pages 1697-1709, "EFFICIENT DOPANTS FOR ZrNiSn-BASED THERMOELECTRIC MATERIALS", 1999
ADF	AX	K. MASTRONARDI, et al., Applied Physics Letters, vol. 74, no. 10, pages 1415-1417, "ANTIMONIDES WITH THE HALF-HEUSLER STRUCTURE: NEW THERMOELECTRIC MATERIALS", March 8, 1999
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

/Anthony Fick/

ADF

Date Considered

01/19/2007

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



LIST OF RELATED CASES

	<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
ADF	221292US2 SRD	10/105,341	03/26/02	SHUTOH et al.
ADF	241072US2 SRD*	10/629,624	07/30/03	SHUTOH et al.

ADF

*Present Application; listed for information

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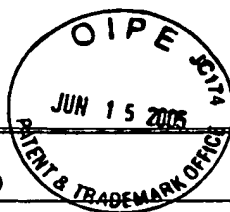
LIST OF RELATED CASES

	<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent Appl. Publication No.</u>	<u>Inventor/ Applicant</u>
ADF	241072US2SRD*	10/629,624	07/30/03		SHUTOH et al.
ADF	260012US2SRD	10/958,376	10/06/04		SHUTOH et al.

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 241072US2SRD		SERIAL NO. 10/629,624	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Naoki SHUTOH, et al.			
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ADF	AR	S. BHATTACHARYA, et al., "Thermoelectric Properties of Sb-Doping In The $\text{TiNiSn}_{1-x}\text{Sb}_x$ Half-Heusler System", 18 th International Conference on Thermoelectrics Proceedings, ICT' 99, August 1999, pages 336-339					
ADF	AS	Y. XIA, et al., "Thermoelectric Properties of semimetallic (Zr, Hf)CoSb half-Heusler phases", Journal of Applied Physics, vol. 88, no. 4, August 15, 2000, pages 1952-1955					
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ADF	AU	Q. SHEN, et al., "Effects of partial substitution of Ni by Pd on the thermoelectric properties of ZrNiSn-based half-Heusler compounds", Applied Physics Letters, vol. 79, no. 25, December 17, 2001, pages 4165-4167					
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ADF	AW	S. Joseph POON, et al., "Electronic and Thermoelectric Properties of Half-Heusler Alloys", Semiconductors and Semimetals, Academic Press, vol. 70, 2001, pages 37-75					
ADF	AX	Shen QIANG, et al., "Synthesis and Thermoelectric Properties of ZrNiSn-based Semi-Heusler Compounds, Preprints of Annual Meeting of The Ceramic Society of Japan, March 21, 2001, page 285					<input type="checkbox"/> Additional References sheet(s) attached
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